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# Automated Chemical Analysis of Internally Mixed Aerosol Particles Using X-ray Spectromicroscopy at the Carbon K-Edge

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**Abstract.**

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4 We have developed an automated data analysis method for atmospheric particles using scanning  
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6 transmission X-ray microscopy coupled with near edge X-ray fine structure spectroscopy  
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8 (STXM/NEXAFS). This method is applied to complex internally mixed submicron particles containing  
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10 organic and inorganic material. Several algorithms were developed to exploit NEXAFS spectral features  
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12 in the energy range from 278-320 eV for quantitative mapping of the spatial distribution of elemental  
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14 carbon, organic carbon, potassium, and non-carbonaceous elements in particles of mixed composition.  
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16 This energy range encompasses the carbon K-edge and potassium L2 and L3 edges. STXM/NEXAFS  
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18 maps of different chemical components were complemented with a subsequent analysis using elemental  
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20 maps obtained by scanning electron microscopy coupled with energy dispersive X-ray analysis  
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22 (SEM/EDX). We demonstrate application of the automated mapping algorithms for data analysis and  
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27 the statistical classification of particles.  
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57 **KEYWORDS.** STXM/NEXAFS, NEXAFS, SEM/EDX, CCSEM/EDX, CCSEM, Aerosol,  
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59 Atmospheric, Carbon, K-Edge, Mixing State, Internally Mixed, Molecular Imaging  
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## Introduction

Aerosol particles have a strong impact on a number of environmental fields including climate change, public health, and atmospheric visibility.<sup>1-3</sup> The magnitude of the aerosol effect on these issues is highly uncertain due to an incomplete understanding of their chemical and physical properties. Atmospheric aerosols have a wide range of sizes, sources, and physicochemical properties. Knowledge of these properties is crucial for understanding aerosol effects, origin, and atmospheric history. However, the chemical characterization of environmental particles presents a significant analytical challenge due to their sub-micrometer size and chemical complexity. With the ability to probe the chemistry of individual particles, modern micro-analytical techniques such as microscopy<sup>4</sup> and micro-spectroscopy<sup>5</sup> are instrumental for overcoming these challenges.

Over the last 40 years, electron beam techniques have been increasingly used to characterize individual particles collected in both laboratory and field settings.<sup>6-9</sup> Scanning electron microscopy coupled with energy dispersive X-ray analysis (SEM/EDX) yields images with ~10 nm lateral resolution and EDX provides elemental analysis. Transmission electron microscopy (TEM) coupled with EDX, selected area electron diffraction (SAED) analysis, or electron energy loss spectroscopy (EELS) is extensively used for particle analysis. TEM spatial resolution is higher than SEM, and SAED can provide crystalline structures. While electron beam microscopy methods have the advantage of exquisite spatial resolution, their elemental analysis is not sufficient to characterize carbonaceous aerosol. Ideally, chemical characterization of carbonaceous particles would employ molecular structure information, or at a minimum, speciation of carbon bonding and/or organic functional groups.

Recently, researchers have pushed the abilities of infrared (IR) and Raman micro-spectroscopy techniques to measure the integrated chemical composition of particle ensembles.<sup>10-14</sup> Although vibrational IR and/or Raman micro-spectroscopy can be non-destructive techniques that provide organic functional group information, their spatial resolution is generally insufficient for single submicron particles. This is due to the inability to focus light beams below the diffraction limit<sup>15</sup> and low signal levels afforded by a single submicron particle.<sup>16,17</sup> Within individual particles, the spatial distribution of

1 chemical compounds affects their chemical and physical properties which in turn affects their  
2 environmental impact. Knowledge of spatially resolved chemical composition also aids in deciphering  
3 particle aging mechanisms and sources.<sup>18,19</sup> Therefore, developing methodologies that accurately map  
4 the internal heterogeneity of individual particles with appropriate statistical depth is important.  
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10 The initial application of STXM to field collected aerosols mapped different organic functional groups  
11 on a limited number of particles.<sup>20</sup> The number of particles examined was limited both by the  
12 experimental time available for data acquisition as well as development of appropriate analytical  
13 methods. Over the past decade, STXM has grown into an active area of research examining topics such  
14 as the graphitic nature of combustion produced aerosols,<sup>21-23</sup> organic particle speciation,<sup>20</sup> the evolution  
15 of aerosol mixing states,<sup>19</sup> and chemical speciation of metal containing aerosols.<sup>24,25</sup> Relating the  
16 detailed analysis of a limited number of particles to the larger, more encompassing statistically  
17 representative picture has been one of the challenges of this method. Some studies have done this by  
18 combining STXM methods with collocated field measurements and complementary electron  
19 microscopies.<sup>19,23,26</sup> This allows the STXM data to be placed within a framework of single particle data  
20 on tens of thousands of particles to millions of particles. Alternatively, STXM results are placed within  
21 the context of complementary bulk information on FTIR, aerosol mass spectrometry or elemental  
22 analysis.<sup>27,28</sup> As access to STXM instruments increases and the method becomes more widely applied,  
23 improved methods of systematic analysis for a statistically significant number of particles are essential.  
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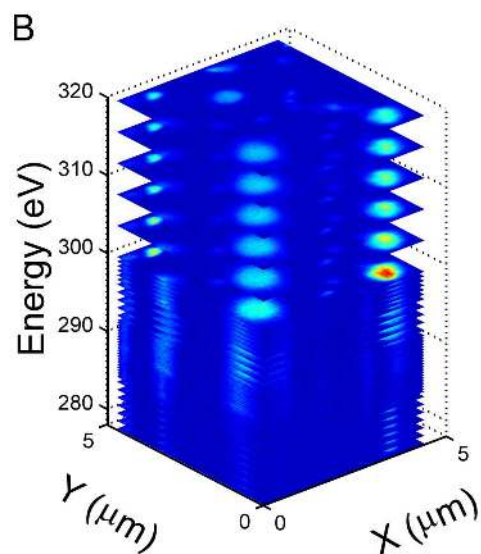
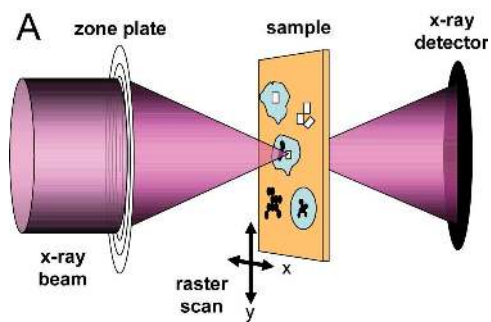
42 This manuscript describes a STXM analytical method for spatially mapping the chemical constituents  
43 commonly identified within individual particles: organic carbon, elemental carbon, and inorganic  
44 species. We present a software assisted methodology for examining the distribution of these three major  
45 components within individual particles. We illustrate how information on non-carbonaceous elements at  
46 the carbon K-edge can be obtained. Using the combined detection of non-carbonaceous inorganic  
47 species, organic carbon, and elemental carbon we generate component maps of individual particles that  
48 can be used for particle-type classification over a large number of particles. The assignment of different  
49 chemical constituents within individual particles is confirmed with SEM/EDX elemental maps. One  
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1 major advantage of this method is that its simplicity allows for a straightforward interpretation and  
2 consistent application across different samples. When applied to multiple datasets, a quantitative  
3 statistical comparison between different particle samples can be obtained. As the reliability and  
4 throughput of STXM instruments increases, there is greater need for methods to perform fast statistical  
5 data analysis for a large number of particles. Additional features can easily be added or changed  
6 depending on the characteristics of a particular sample. This analytical framework is applicable to a  
7 variety of environmental samples other than atmospheric particles; examples include: soils, meteorites  
8 and interplanetary dust, and nanoparticles.  
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## 19 **Methods**

20 Particle samples. Samples of airborne particles were collected by impaction using a time resolve  
21 aerosol collector (TRAC).<sup>29</sup> Substrates of either Si<sub>3</sub>N<sub>4</sub> film supported by a silicon wafer (0.5 × 0.5 mm  
22 Si<sub>3</sub>N<sub>4</sub> window size, 100 nm Si<sub>3</sub>N<sub>4</sub> membrane thickness, 5 × 5 mm Si frame size; Silson, Inc.) or filmed  
23 TEM grids (Carbon type B film, Copper 400 mesh grids; Ted Pella, Inc.) were used as impaction  
24 substrates. The particle samples were collected in Mexico City during the MILAGRO 2006 campaign at  
25 the T0 sampling site.<sup>19,24</sup> Sea salt particles were generated from a 40 g/L aqueous solution prepared from  
26 sea salts (Sigma Aldrich) and 18.0 MΩ Milli-Q water. The salt solution was atomized using a flow of  
27 nitrogen and particles were sampled using an inertial impactor onto silicon nitride films as described  
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43 STXM Measurements. The STXM instruments used in this study are located at the Advanced Light  
44 Source at Lawrence Berkley National Laboratory. However, the analysis techniques presented here are  
45 applicable at the majority of STXMs operating throughout the world as they employ the identical data  
46 acquisition software. The design principle of the STXM instrument has been described in detail  
47 elsewhere.<sup>30</sup> The basic components of the STXM instrument are shown in Figure 1A. The  
48 monochromatic soft X-ray beam produced at the synchrotron source is focused by a Fresnel zone plate  
49 to a spot size between 20 and 40 nm, depending upon the zone plate used. The sample is held at the  
50 focal point of the monochromatic X-ray beam and raster scanned to obtain an image. X-rays transmitted  
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**Figure 1.** Schematic of the STXM instrument: (A) – basic operation and measurement diagram, (B) - a spectral “stack” of images collected for a single field-of-view of the analyzed sample.

1 through the sample are detected by a thin layer of phosphor coating on a Lucite light pipe coupled to a  
2 photodiode. After an image is collected at a fixed energy, the energy is changed and the sample is  
3 scanned again. This process continues for ~100 unevenly spaced energy steps and results in a “stack” of  
4 images as demonstrated in Figure 1B. The energy steps are typically smaller in the near edge energy  
5 range (285 – 294 eV) to capture narrow spectral features present in that region.  
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11 SEM/EDX measurements. A FEI XL30 digital field emission gun environmental SEM located at  
12 Environmental Molecular Sciences Laboratory of Pacific Northwest National Laboratory was used for  
13 SEM/EDX analysis. The system is equipped with Genesis hardware and software (EDAX, Inc.) for X-  
14 ray microanalysis and elemental mapping. The EDX spectrometer has a Si(Li) detector with an active  
15 area of 30 mm<sup>2</sup> and ATW2 window, which allows X-ray detection from elements higher than beryllium  
16 (Z > 4). The X-ray maps were acquired at 10,000× magnification, with 512 × 400 pixel map resolution,  
17 a beam current of ~500 pA, and an accelerating voltage of 20 kV. Maps of C, N, O, Na, Mg, Si, S, Cl,  
18 and K were selected based on the high abundance of these elements in the sample.<sup>19</sup> Additional details  
19 of SEM/EDX particle analysis are found elsewhere.<sup>9</sup>  
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33 Data Processing. After data acquisition, the ASCII formatted “stack” of STXM images (.xim) and  
34 STXM header file (.hdr) is imported into MATLAB<sup>TM</sup> for further data processing and analysis. A  
35 processing routine first aligns<sup>31</sup> the images to correct for image drift encountered during data  
36 acquisition. Particle contours within the image are identified using Otsu’s method.<sup>32</sup> This method locates  
37 the particle contour by separating the image pixels into background and sample classes based on their  
38 intensity; the separation threshold is determined to be that which minimizes the intra-class variance. All  
39 pixels below the threshold set by Otsu’s method are taken to be the regions yielding the intensity  
40 transmitted through the particle (*I*). The particle-free image pixels yield the background intensity (*I*<sub>0</sub>).  
41 The aligned “stack” of images is then converted to optical density (OD or absorbance) using the relation  
42  $OD = -\ln(I/I_0)$  and saved as MATLAB<sup>TM</sup> binary files (.mat) for further analysis. This process has been  
43 fully automated and scripts are available at  
44 <http://www.mathworks.com/matlabcentral/fileexchange/24006>. These scripts can be used for  
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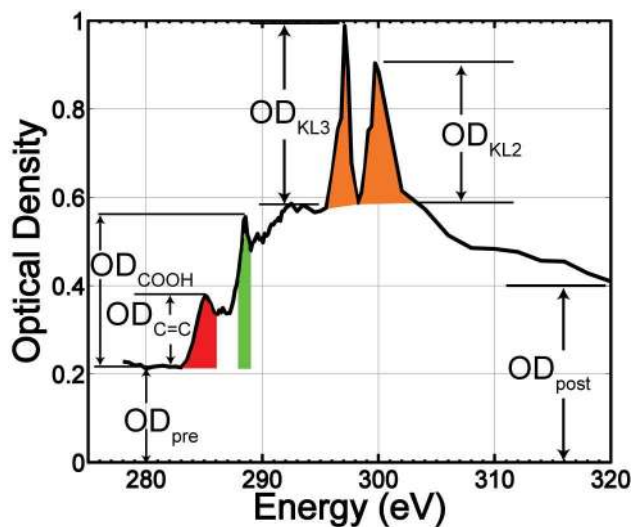
1 applications where statistical approaches are needed, such as engineered and environmental  
2 nanoparticles or modified for other absorption edges. Furthermore, a graphical user interface is provided  
3 for data exploration. Routines for performing singular value decomposition (SVD), principal  
4 components analysis (PCA) and clustering are included. For performing positive matrix factorization  
5 (PMF),<sup>33</sup> the program “PMF2” was utilized using FPEAK=-1.5; standard deviations for each pixel were  
6 taken to be the standard deviation of its first 10 pre-edge energy points. Particle-free regions were  
7 excluded from the PMF analysis.  
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9 For processing, the SEM/EDX elemental maps were first converted into binary images using Otsu’s  
10 method and subsequently noise-filtered. For the S + O map, the pixels were intersected to produce a  
11 combined map. After grouping, all binary maps were exported to Photoshop<sup>TM</sup> and individual colors  
12 assigned for each of the elemental maps. An image containing the combined set of elemental maps with  
13 80-90% opacity applied to each map was created and overlaid on the secondary electron microscopy  
14 image.  
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## 16 Results

17 **Basic features of Carbon K-edge Spectrum.** A typical single particle carbon K-edge  
18 (transition from the 1s orbital) near edge X-ray absorption fine structure (NEXAFS) spectrum (Figure 2)  
19 contains contributions from several components common in atmospheric particles. The optical density  
20 from 278 - 283 eV is known as the pre-edge ( $OD_{pre}$ ). For typical atmospheric particles the pre-edge  
21 offset is mainly due to off-resonance absorption by inorganic elements other than carbon.<sup>34</sup> The post-  
22 edge region at 320 eV ( $OD_{post}$ ) contains contributions from both carbonaceous and non-carbonaceous  
23 atoms. The near-edge region, which arises from absorption by carbon 1s transitions, contains several  
24 peaks of potential interest between 285 and 290 eV. Here, we focus on the most prominent and  
25 unambiguous peaks. The peak at 285.4 eV is due to the characteristic transition ( $C\ 1s \rightarrow \pi^*_{C=C}$ ; \*  
26 represents the excited state) of  $sp^2$  hybridized carbon (doubly bonded carbon), labeled  $OD_{C=C}$ . Since the  
27  $C\ 1s \rightarrow \pi^*_{C=C}$  peak is abundant for soot or elemental carbon (EC),<sup>35</sup> it can be used to identify soot as  
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**Figure 2.** Characteristic single particle carbon K-edge near edge X-ray fine structure (NEXAFS) and spectral feature assignments: “pre-edge” (OD<sub>pre</sub>) occurs between 278 and 283 eV, carbon-carbon double bonds (OD<sub>C=C</sub>) shown in red, carboxylic acids (OD<sub>COOH</sub>) shown in green, potassium L<sub>2</sub> and L<sub>3</sub> edges (OD<sub>KL3</sub>, OD<sub>KL2</sub>) shown in orange. OD<sub>post</sub> is the post absorption edge at 320 eV.

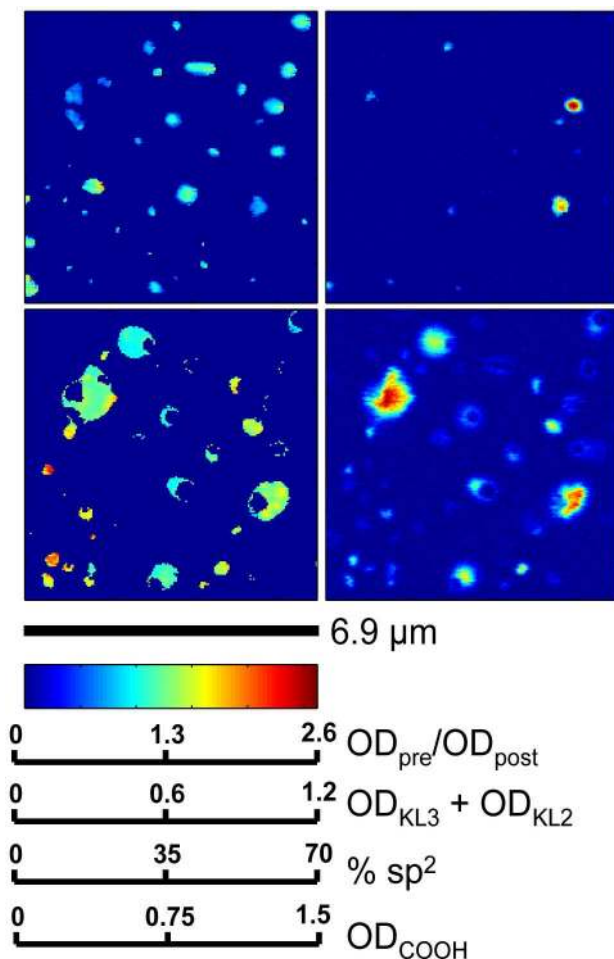
described in detail below. The second peak of interest, at 288.5 eV, is characteristic of the C 1s  $\rightarrow \pi^*_{R(C^*=O)OH}$  transition for COOH groups (OD<sub>COOH</sub>), which are often abundant in atmospheric organic particles.<sup>20,23,36</sup> Therefore, organic constituents are identified by the 288.5 eV peak. A distinct carbonate peak (not shown in Figure 2), often present in dust and sea salt, is observed at 290.4 eV. Finally, the two peaks shaded orange (Figure 2) correspond to the L<sub>2</sub> and L<sub>3</sub> edges of potassium (labeled OD<sub>KL2</sub> and OD<sub>KL3</sub>). Potassium in carbonaceous particles is usually apportioned to mineral dust or biomass burning emissions (e.g. biofuel, cooking, wildfires etc.).<sup>37,38</sup>

Figure 3 shows corresponding maps of the four components identified in Figure 2. To reduce noise, pixels less than three times the standard deviation of the pre-edge background are set to zero. OD<sub>pre</sub> is proportional to the number of non-carbon atoms and OD<sub>post</sub>-OD<sub>pre</sub> is proportional to the number of carbon atoms.<sup>34</sup> Hence, the ratio OD<sub>pre</sub>/OD<sub>post</sub> can be an indicator of inorganic (“In”) material in individual particles. The exact relationship between OD<sub>pre</sub>/OD<sub>post</sub> is quantitatively explored below for a variety of inorganic species. In the map of OD<sub>pre</sub>/OD<sub>post</sub> shown in Figure 3, the regions of high OD<sub>pre</sub>/OD<sub>post</sub> are characterized by compact objects, with the largest ratio occurring in the particle centers.

Potassium peak intensities (OD<sub>KL2</sub> and OD<sub>KL3</sub>) were quantified after subtracting the carbon contribution from the spectra. Two straight lines beneath the potassium peaks were calculated using energies between 294 to 295 eV and 302 to 305 eV. The values of these lines at the energy positions of the two potassium peaks were subtracted from the total peak height, giving the quantities OD<sub>KL2</sub> and OD<sub>KL3</sub>; these quantities are indicated schematically by heights of the orange peaks in Figure 2. The quantity reported for the “K” component map in Figure 3 is a sum of OD<sub>KL2</sub> and OD<sub>KL3</sub>.

The spatial distribution of carbon-carbon double bonds is shown in the % sp<sup>2</sup> map (Figure 3). Employing the procedure of Hopkins et al.<sup>22</sup> the % sp<sup>2</sup> hybridization at each pixel was calculated:

$$\%sp^2 = \left( \frac{A_{C=C}^{Sample}}{A_{280-320}^{Sample}} \right) \left( \frac{A_{280-320}^{HOPG}}{A_{C=C}^{HOPG}} \right) \cdot 100.$$

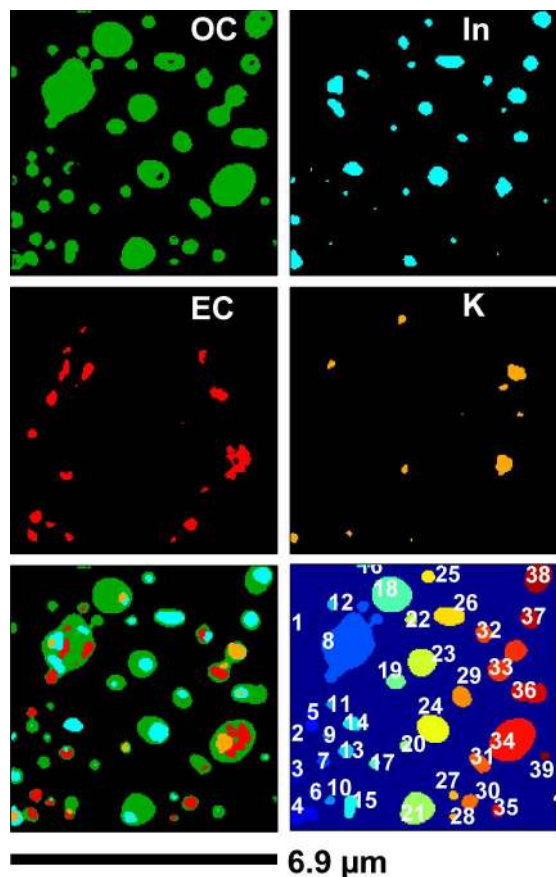
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**Figure 3.** STXM particle maps indicating different spectral components identified in Fig 2:  $OD_{pre}/OD_{post}$  represents total carbon absorption,  $OD_{KL3} + OD_{KL2}$  is a potassium map (orange peaks in Figure 2),  $\% sp^2$  shows carbon-carbon double bonds (red peak in Figure 2) and  $OD_{COOH}$  is a map of carboxylic acid groups (green peak in Figure 2).

1  $A_{C=C}^{Sample}$  is the area of the C 1s  $\rightarrow \pi^*_{C=C}$  peak (285.4 eV) and  $A_{280-320}^{Sample}$  is the total area of the carbon K-  
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3 edge spectrum.  $A_{C=C}^{HOPG}$  is the total area of carbon K-edge spectrum for highly oriented polycrystalline  
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5 graphite (HOPG) and  $A_{280-320}^{HOPG}$  the area of the C 1s  $\rightarrow \pi^*_{C=C}$  peak for HOPG reported by Lenardi et al.<sup>39</sup>  
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8 HOPG is assumed to contain 100%  $sp^2$  hybridized bonds. The resulting %  $sp^2$  map (Figure 3) indicates  
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10 distinct particle regions that are rich in  $sp^2$  or C=C bonds. While some of the  $sp^2$  rich regions are non-  
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12 spherical or compact as expected for atmospheric soot particles, several regions are on the periphery  
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14 coating of the particles, which is indicative of organic carbon. Most of these coatings have lower %  $sp^2$   
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16 values than the soot particles. In the next section, this information is employed to identify soot  
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18 inclusions.  
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23 The C 1s  $\rightarrow \pi^*_{R(C*=O)OH}$  transition was used to map particle regions containing organic material.  
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25 The organic carbon (OC) map (Figure 3 lower right hand panel) is based on the height of the baseline-  
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27 subtracted carboxylic acid peak ( $OD_{COOH}-OD_{pre}$ ). The C 1s  $\rightarrow \pi^*_{R(C*=O)OH}$  transition provided the best  
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29 contrast for organic carbon due to its prominence in the NEXAFS spectrum shown in Figure 2. Based on  
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31 Figure 3, we surmise that organic material normally coats inorganic-rich regions. This is consistent with  
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33 organic material from the gas phase condensing onto existing particles.  
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37 **Component Detection Thresholds for Mixing State Determination.** A crucial step in  
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39 statistically analyzing internally-mixed particles is identifying the entire particle and specific  
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41 components within each particle that define the mixing state. Figure 4 shows component binary maps  
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43 produced by identifying species above the detection thresholds defined in this section. The total particle  
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45 area (Figure 4, lower right) was automatically compared to each component binary map to associate the  
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47 component with each particle. If a portion of a component map overlapped with the particle area then  
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49 the particle was assigned the label for that component. For example, in the bottom panels of Figure 4,  
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51 particle #34 was labeled as InKECOC and particle #37 was labeled as InOC. This labeling procedure  
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53 was used to report particle type number fractions in Mexico City samples.<sup>19</sup> Hence, it is critical that the  
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**Figure 4.** Binary component maps after applying a threshold for organic carbon (OC), inorganic (In) constituents, elemental carbon (EC, or soot), and potassium (K) containing salts. The lower left panel shows the total mixed particle composition with images overlaid in the following order 1) OC, 2) In 3) K 4) EC. The lower right panel shows particle identification indices. From the combined map, particle mixing states are identified. For example, particle #12 is identified as OC, #34 as InKECOC, #38 as InOC, and # 37 as InOC.

1 thresholds used to produce the binary images shown in Figure 4 are quantitative and reproducible.  
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3 Therefore, the threshold definitions are detailed below.

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5 To obtain the total particle area, an image of the average OD at each pixel between 288 and 295 eV is  
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7 obtained. By raising the OD for each pixel in the resulting image to the power of 0.2, the contrast of thin  
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9 particle coatings or residues are accentuated. Subsequently, Otsu's method is applied to calculate a  
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11 threshold for producing a binary map of the particle areas. The lower right-hand panel of Figure 4  
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13 illustrates an example of the resulting particle areas identified using this procedure.

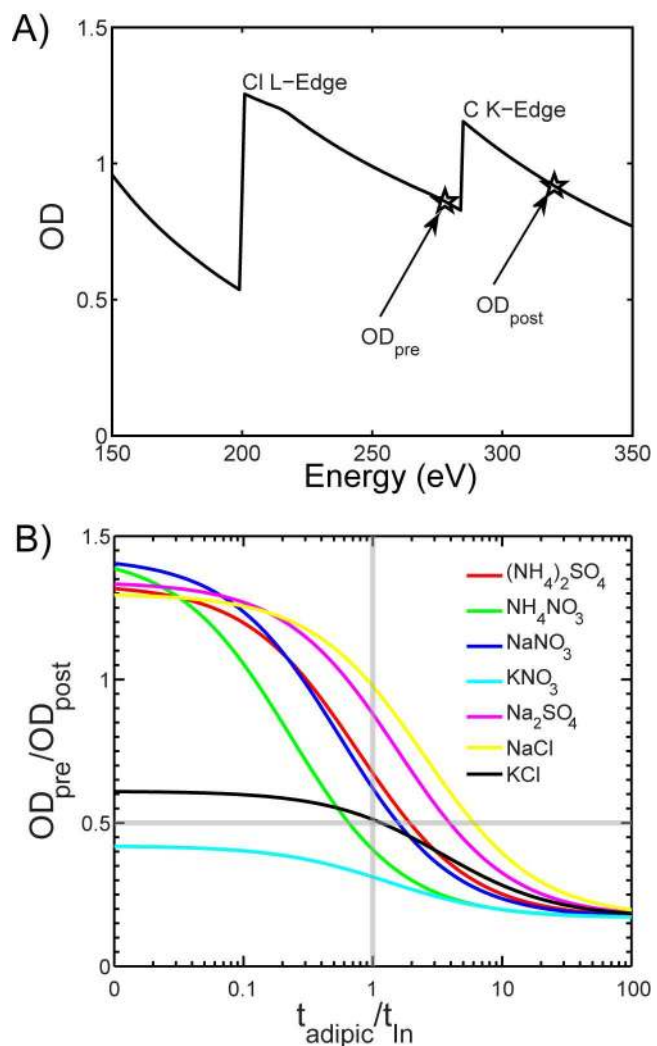
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15 To identify the organic component, Otsu's method is applied to the contrast-adjusted  $OD_{\text{COOH}}$ -  
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17  $OD_{\text{pre}}$  map in Figure 3. The detection threshold from Otsu's method is then used to produce the binary  
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19 map shown in Figure 4. For the In, K and EC components (Figure 3), fixed thresholds were used to  
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21 produce binary maps as described below.  
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25 Elemental carbon (EC, or soot) regions of the samples are identified based on a fixed %  $sp^2$   
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27 value of 35%. This value was determined empirically from the observation that the organic carbon rings  
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29 surrounding the particles disappeared at or above the threshold level (Figure S-1).<sup>5</sup> Only compact and  
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31 non-spherical inclusions remain in the maps with thresholds at or above 35%  $sp^2$  (Figure 4), which is  
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33 consistent with previous observations of soot morphology.<sup>40</sup> Furthermore, spectra from pixels below the  
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35 threshold level more closely resemble organic carbon (Figure S-1).  
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39 As noted previously,  $OD_{\text{pre}}/OD_{\text{post}}$  is an indicator of non-carbonaceous constituents in the particle.  
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41 This is because  $OD_{\text{pre}}$  is proportional to the number of non-carbon atoms and  $OD_{\text{post}} - OD_{\text{pre}}$  is  
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43 proportional to the number of carbon atoms.<sup>34</sup> Figure 5A is a spectrum calculated from the atomic cross  
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45 sections of adipic acid and NaCl. Figure 5A demonstrates the contribution of the inorganic species (e.g.  
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47 Cl) to  $OD_{\text{pre}}$  and the contribution of carbon to  $OD_{\text{post}}$ . A more quantitative interpretation of the pre-to-  
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49 post edge ratio can be determined with the Beer-Lambert law. The OD of an arbitrary chemical species  
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$$56 \quad OD = -\ln\left(\frac{I}{I_0}\right) = \mu(E)\rho t \quad (1)$$

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**Figure 5.** A) Calculated atomic absorption from a mixture of adipic acid and NaCl (each 100 nm thick). The absorption below 150 eV is primarily due to the Na-L edges. B) Calculated pre-edge to post-edge ratios (OD<sub>pre</sub>/OD<sub>post</sub>) as a function of the thickness ratio between adipic acid and inorganic salts common in atmospheric aerosols. For the In map in Figure 4, a threshold of OD<sub>pre</sub>/OD<sub>post</sub> > 0.5 was used to identify inorganic inclusions.

where  $\rho$  is the mass density of the material,  $t$  is the sample thickness and  $\mu$  is the mass absorption coefficient. For a chemical compound containing  $x_i$  atoms of element  $i$  that have an atomic number  $Z_i$ , the mass absorption coefficient at energy  $E$  can be calculated as:

$$\mu(E) = \frac{\sum_i Z_i x_i \mu(E)_i}{\sum_i x_i Z_i} \quad (2)$$

Typical atmospheric organic particulate matter has an atomic oxygen-to-carbon ratio of about 0.5.<sup>41</sup> Here, the dicarboxylic acid, adipic acid (hexanedioic acid  $(\text{CH}_2)_4(\text{COOH})_2$ , with an atomic ratio O/C = 0.67 and  $\rho = 1.36 \text{ g/cm}^3$ ) is used as a proxy for organic particulate matter. Using Equations 1 and 2 for a particle containing a mixture of adipic acid and an inorganic salt (“In”), the pre-to-post edge ratio is expressed in terms of the thickness ratio ( $t_{\text{adipic}}/t_{\text{In}}$ ):

$$\frac{OD_{\text{pre}}}{OD_{\text{post}}} = \frac{\mu_{\text{adipic}}(278 \text{ eV})\rho_{\text{adipic}} \frac{t_{\text{adipic}}}{t_{\text{In}}} + \mu_{\text{In}}(278 \text{ eV})\rho_{\text{In}}}{\mu_{\text{adipic}}(320 \text{ eV})\rho_{\text{adipic}} \frac{t_{\text{adipic}}}{t_{\text{In}}} + \mu_{\text{In}}(320 \text{ eV})\rho_{\text{In}}} \quad (3)$$

The term  $\mu_{\text{adipic}}(278 \text{ eV})\rho_{\text{adipic}}$  is about an order of magnitude smaller than  $\mu_{\text{In}}(278 \text{ eV})\rho_{\text{In}}$  for common atmospheric inorganic salts.

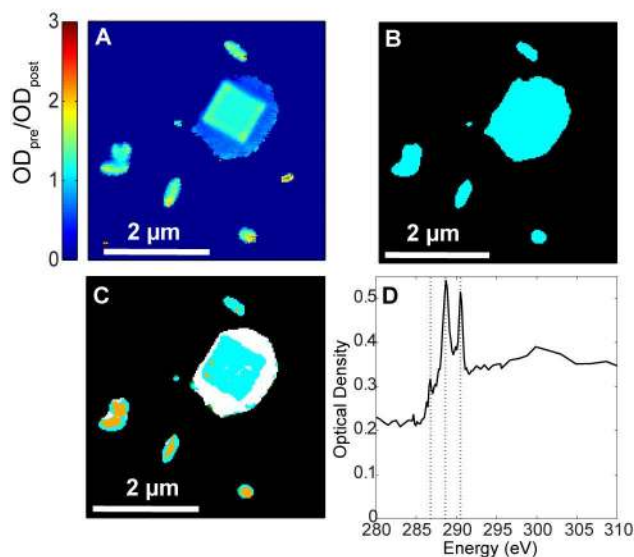
Figure 5B shows the  $OD_{\text{pre}}/OD_{\text{post}}$  ratios calculated as a function of the  $t_{\text{adipic}}/t_{\text{In}}$  thickness ratios for several mixtures of adipic acid and inorganic salt using eq. 3. Atomic scattering is neglected because it is roughly three orders of magnitude smaller than absorption at these energies.<sup>42</sup> These trends hold for a variety of metal and aluminosilicate compounds (Figure S-2). Because potassium salts have an ionization edge over a similar energy range as carbon,  $OD_{\text{pre}}/OD_{\text{post}} < 1$  for all mixtures of potassium salts and organics (Figures 5B, S-3); Pb compounds have the same characteristic (Figure S-2). For pure inorganic salts ( $t_{\text{adipic}}/t_{\text{In}} = 0$ ),  $OD_{\text{pre}}/OD_{\text{post}} \sim 1.3$  and is an indicator of the slope of the absorption tail due to the inorganic species (Figure 5A). For thick organic coatings ( $t_{\text{adipic}}/t_{\text{In}} > 1$ ),  $OD_{\text{pre}}/OD_{\text{post}}$  converges to a value of 0.19. Generally, as the organic O:C atomic ratio increases,  $OD_{\text{pre}}/OD_{\text{post}}$  also increases (Figure



1 S-2). For example, graphite (O:C = 0)  $OD_{pre}/OD_{post} = 0.06$ , glucose (O:C = 1)  $OD_{pre}/OD_{post} = 0.24$  and  
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3 oxalic acid (O:C = 2)  $OD_{pre}/OD_{post} = 0.36$ . As a result, highly oxidized organic particles provide more  
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5 sensitive detection of inorganic species (Figure S-3). Most importantly, most mixed particles with a pre-  
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7 edge to post-edge ratio above 0.5 have compositions (on a thickness basis) dominated by inorganic  
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9 material (Figures 5B and S-3).  
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11 Based on this analysis, the threshold for mapping inorganic (In) content was set at  $OD_{pre}/OD_{post} = 0.5$ .  
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13 From the mixed component map (Figure 4), it is seen that the inorganic regions (blue areas) appear as  
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15 inclusions surrounded by an organic coating (green areas). Comparing maps in Figures 3 and 4, it is  
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17 apparent that the amount of COOH at the inorganic inclusions is lower than the surrounding particle  
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19 regions. The threshold value of 0.5 was tested on a variety of different particle samples: carbonaceous  
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21 urban particles from Mexico City,<sup>19</sup> sea salt coated with organics, and a variety of mineral dust particles.  
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23 For each of these samples, the inorganic region was accurately mapped using the threshold value of  
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25  $OD_{pre}/OD_{post} = 0.5$ .  
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30 Figure 6A shows  $OD_{pre}/OD_{post}$  for a sea salt particle. As expected, areas corresponding to cubic NaCl  
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32 indicate a high  $OD_{pre}/OD_{post}$  ratio. In fact, the majority of the area of the cubic NaCl particle has an  
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34  $OD_{pre}/OD_{post}$  ratio  $\sim 1.3$ , which corresponds to pure NaCl (Figure 5). This is consistent with Figure 3,  
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36 where the majority of the particles also have a maximum  $OD_{pre}/OD_{post}$  ratio of  $\sim 1.3$ . For pure NaCl, the  
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38 value of  $OD_{pre}/OD_{post}$  arises from the negatively sloped absorption edge tail from Na and Cl atoms  
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40 (Figure 5A). Figure 6B shows regions containing inorganic material determined by setting the threshold  
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42 value of  $OD_{pre}/OD_{post} > 0.5$ . It is immediately apparent that not only is the cubic NaCl mapped, but also  
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44 the coating surrounding the NaCl crystal. Figures 6C and 6D show that this coating contains CO<sub>3</sub> and  
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46 COOH. It should be noted that for thick particles such as the center of the cubic NaCl particle in Figure  
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48 4, organic identification can be problematic due to non-linearities. Nevertheless, CO<sub>3</sub> was mapped using  
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50 a methodology similar to that used for potassium but over the energy range suitable for CO<sub>3</sub>. The  
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52 overlap of CO<sub>3</sub> with the inorganic regions (Figures 6B and 6C), provides further confirmation of the  
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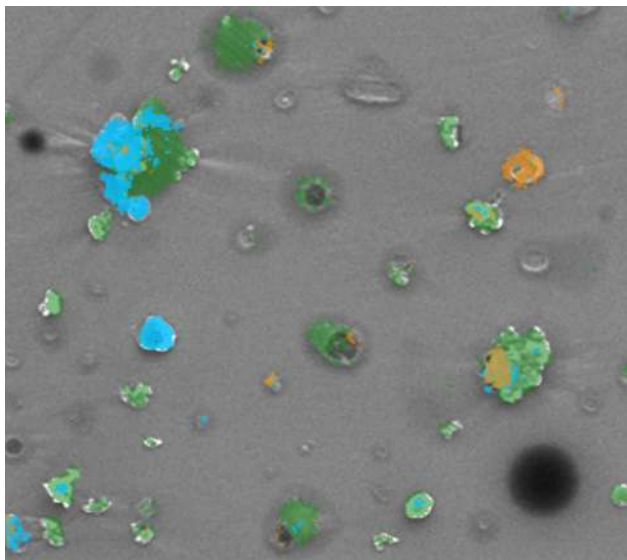
**Figure 6.** STXM/NEXAFS maps of a sea salt particle: A) the pre edge to post edge ratio ( $OD_{pre}/OD_{post}$ ). Values of  $OD_{pre}/OD_{post}$  are depicted by the color scale., B) binary map of areas having  $OD_{pre}/OD_{post} > 0.4$  C) binary component map showing potassium (orange), inorganic areas (blue), CO<sub>3</sub> (white) and organics (green, not visible as displayed). Panel D shows the spectrum taken over the regions containing CO<sub>3</sub> and organics.

1 threshold level for “In” identification. Therefore, the  $OD_{pre}/OD_{post}$  threshold of 0.5 appears robust for  
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3 identifying inorganic inclusions in mixed atmospheric particles.  
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5 **Comparison with SEM Elemental Maps.** To confirm the particle components identified by  
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7 the STXM mapping procedure at the carbon K-edge, the particles shown in Figures 3 and 4 were  
8  
9 subsequently mapped using SEM/EDX. Figure 7 shows a secondary electron (SE) image with elemental  
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11 maps obtained with SEM/EDX overlaid. The EDX elemental maps provide a detailed elemental picture  
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13 of the inorganic regions, while the SE image provides a higher resolution view of the carbonaceous  
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15 component (sum of EC and OC). Comparison of Figure 7 and the particles regions identified by STXM  
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17 (Figure 4, bottom right) reveals that the smallest (<200 nm) particles in the SE image were not identified  
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19 as particles using the current STXM mapping routines.  
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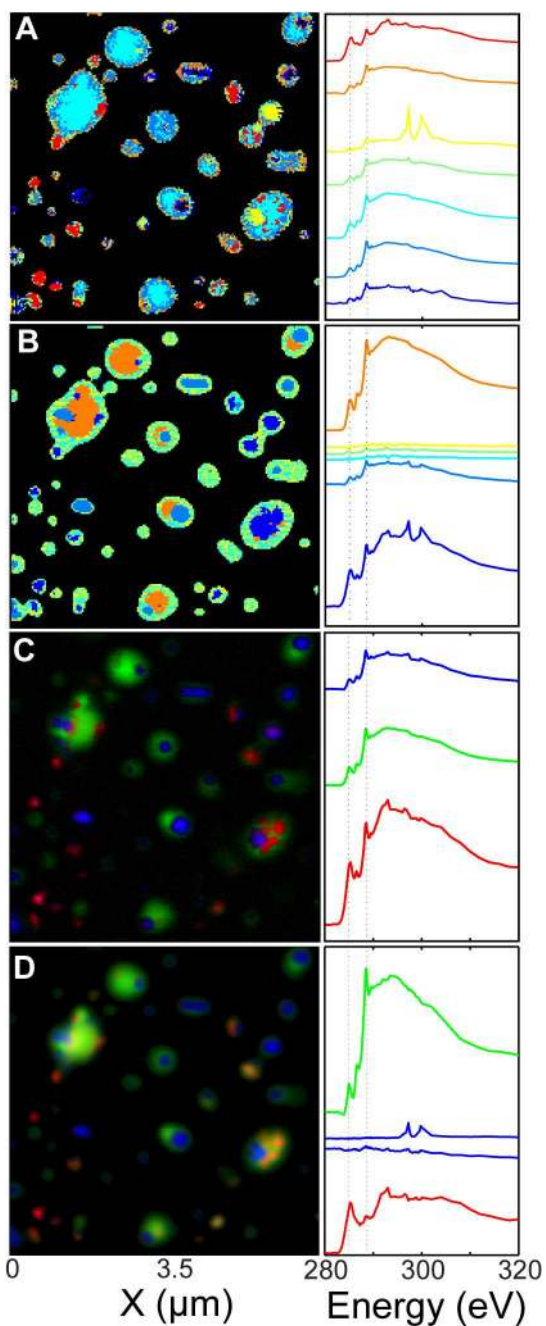
24 The green transparent color in Figure 7 indicates the carbon rich regions identified by EDX elemental  
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26 mapping. Comparing Figures 4 and 7, many of the green regions in the SEM/EDX map are associated  
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28 with both elemental carbon EC and organic carbon (OC) as identified by the STXM. The brighter  
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30 regions of the secondary electron image that overlap with carbon are particularly rich in elemental  
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32 carbon as identified by STXM (Figure 4)—these show up as lighter shades of green in Figure 7. The  
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34 maps for potassium obtained by SEM and STXM, indicated by the orange regions in Figures 7 and 4,  
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36 are in excellent agreement. Lastly, regions containing sulfur and oxygen in Figure 7 agree well with the  
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38 inorganic regions identified by the STXM mapping. However, SEM/EDX maps identified fewer  
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40 inorganic regions than STXM maps. This may be due to beam damage of sensitive inorganic species  
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42 (such as ammonium sulfate) by either STXM or SEM.  
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47 **Comparison with other STXM mapping methods.** A variety of analysis techniques have  
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49 been employed to produce chemical maps from STXM data including: clustering,<sup>43</sup> principal component  
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51 analysis (PCA) coupled with a clustering algorithm,<sup>44</sup> singular value decomposition (SVD),<sup>45</sup> and  
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53 positive matrix factorization (PMF).<sup>43</sup> Figure 8 demonstrates the application of each of these mapping  
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55 techniques to the data set used for Figures 3 and 4.  
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**Figure 7.** SEM secondary electron image with EDX elemental maps overlaid: C –green, K- orange, S+O – blue.



**Figure 8.** Composition maps (left) and representative spectra (right) at the carbon K-edge derived for the same sample using different mapping methods: A) clustering of particle spectra, B) PCA + clustering, C) SVD using components derived from composition maps, D) PMF. The color of each spectrum corresponds to the same color in the corresponding chemical map (left panels).

1 Figure 8A shows cluster spectra (right) and a map of their distribution (left) derived using the k-means  
2 clustering algorithm. Clustering of spectra results in a binary classification: each pixel is assigned to a  
3 single component. Clustering identifies some of the major compositions within the particles (EC, K,  
4 OC, In). Notably, clustering identifies differences in the organic component which arise due to the  
5 higher relative contribution of the carbon K-edge  $1s \rightarrow \pi^*_{\text{RCOOH}}$  and lower total carbon at the thin  
6 particle edges. However, some morphological information is lost by displaying the cluster images  
7 (compare Figures 7 and 4 with Figure 8A).  
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10 Figure 8B shows cluster maps and spectra produced by combining PCA and clustering analysis. The  
11 advantage to performing clustering after PCA is that physical spectra are obtained.<sup>44</sup> Furthermore,  
12 performing PCA prior to clustering results in much smoother composition maps. However, as with  
13 clustering, much of the morphological and optical thickness information is lost with the binary cluster  
14 classification. By performing PCA, some aspects of the composition map produced solely by clustering  
15 are lost (such as the variations in organic carbon and potassium).  
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18 Figure 8C demonstrates the particle composition map derived by performing SVD using spectra  
19 provided by the map regions indicated in Figure 4. The SVD map is not a binary classification (as with  
20 PCA and/or Clustering) and each pixel has a color intensity that is related to the amount of material  
21 present. As expected, the SVD map produces a similar depiction of particle morphology compared to the  
22 threshold maps (Figure 4). Furthermore, if the composition is known and carefully calibrated spectra are  
23 used in the SVD algorithm, SVD can be mass quantitative.  
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26 PMF yields a composition map (Figure 8D) similar to the SVD map. However, the factors derived  
27 using PMF more closely resemble pure components. For instance, the EC factor (red) resembles a  
28 spectrum of freshly generated flame soot.<sup>22</sup> The PMF results are remarkable because of the limited *a*  
29 *priori* information provided, i.e. 1) the number of factors and 2) a parameter called FPEAK (set at -1.5  
30 for this study). With SVD, the spectra of each component must be provided. In principal, assuming the  
31 physical properties of the pure components are known, the PMF composition maps can be mass  
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1 quantitative. However, FPEAK and the number of factors needed to produce reasonable (as determined  
2 by the experimenter) spectral maps may need to be changed manually, making automation difficult.

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5 One disadvantage of the PMF, SVD, and PCA techniques is that they require *a priori* knowledge  
6 about the sample to map components consistently in an automated fashion. Unfortunately, *a priori*  
7 knowledge on natural samples or typical environmental particles is usually limited. Information such as  
8 the number of factors (chemically distinct components), or other parameters particular to the algorithm  
9 will vary from region to region within a sample (as well as among different samples) due to the natural  
10 variation in composition. For clustering, relating a set of clusters from one analysis region to another is  
11 difficult. Without evaluating these *a priori* assumptions in detail, one cannot be certain of the accuracy  
12 of the analysis. This increases the complexity of the analysis and the difficulty of defining particle  
13 classes for a statistical analysis.  
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## 25 26 27 **Conclusion.**

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29 The mapping method presented here is a simple, automated way to produce spatial maps of basic  
30 components typically found in atmospheric particles. We developed a quantitative mapping technique to  
31 identify inorganic material for a statistical analysis. Given that the STXM/NEXAFS technique is  
32 element specific, this methodology enables the identification of both inorganic (non-carbonaceous) and  
33 organic species at the C K-edge. For EC mapping, the previous approach of using the percentage of  $sp^2$   
34 hybridized bonds was employed.<sup>22</sup> The identification of OC, EC and inorganic regions of particles was  
35 confirmed using SEM/EDX. The simplicity of the method described here makes automated analysis  
36 facile, significantly reduces analysis time and human bias while comparing different particle samples.  
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38 Such a detailed, automated comparison cannot be obtained using other methods requiring *a priori*  
39 information such as PMF, PCA or clustering. This automated method was recently used to analyze  
40 differences in over 1000 particles collected at different times and locations in Mexico City to examine  
41 the effects of atmospheric aging on internally mixed atmospheric aerosol particles.<sup>19</sup>  
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57 In general, environmental particles are complex mixtures containing variable amounts of (often  
58 unknown) organic and inorganic species. The molecular complexity of organic aerosol leads to  
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1 additional challenges and requires simplification of the image region under study. Furthermore, the  
2 spatial mixing of EC with other components affects their optical properties and potentially influences  
3 global climate.<sup>46</sup> Therefore, it is necessary to isolate the regions within individual particles for detailed  
4 analysis and modeling of single particle optical properties. The technique presented in this manuscript  
5 allows effective isolation of distinctive regions within multi-component particles. Individual, internally  
6 mixed particles may be spatially analyzed and the results combined with other particles analyzed the  
7 same manner for a statistical representation of the particle population. This spatially resolved approach  
8 to single-particle analysis can readily be applied to problems related to climate change, e.g.  
9 morphological effects on optical properties or effects of mixed organic-inorganic particles on cloud  
10 formation and hygroscopic growth. More broadly, this approach is also suitable for environmental  
11 systems such as soil samples, meteorites, or biological samples where statistically significant results are  
12 desired for meaningful interpretation rather than extremely detailed results on a single particle or  
13 sample.  
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4 Functional Systems).  
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10 Supporting Information Available: This material is available free of charge via the Internet at  
11 <http://pubs.acs.org>.  
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